Technical Notes

1. Summary

This memo is the improvement requirement of NVDIMM bypass test and NV FCT

2. Content

2.1 Add test log to EEPROM below address when donging bypass and NV FCT testing

Byte	Hex Value	ASCII	Function Description	Value Description	Remark
2A3	0x01	/	Bypass Test Counts	1 time	**Integer**
2A4	0x46	F	Bypass Test Result	Fail	ASCII
2A5	0x02	/	NV FCT Counts	2 times	**Integer**
2A6	0x50	P	NV FCT Result	Pass	ASCII

For test time counts, record the test time before shipping, e.g. if the board was tested once, the counts should be "1", if the board was tested twice, the counts should be "2";

For test result, record the final test result, if pass fill "P", if fail fill "F"

2.2 Design a SW to read out the test counts and test result, if the test time is blank or test result is blank/"F", the test will be fail, record the test counts and test result in test log
   2.2.1   Use IIC tool and debug board to read out the test information from the EEPROM
   2.2.2   The SW will be triggered to start by scan SN bar code
   2.2.3   The read out test information will be record in a test log and link to shop floor record

SW design proposal:

AgigA CTU will modify current Bypass and NV FCT SW to add the function to record test counts and result
CY Shanghai help to create a SW to check the test log information, record test result and link to shopfloor system

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